Abstract

A MOS semiconductor device includes n^--type surface regions, which are extended portions of an n^--type drift layer 12 extended to the surface of the semiconductor chip. Each n^--type surface region 14 is shaped with a stripe surrounded by a p-type well region. The surface area ratio between n^--type surface regions 14 and p-type well region 13 including an n^+-type region 15 is from 0.01 to 0.2. The MOS semiconductor device further includes, in the breakdown withstanding region thereof, a plurality of guard rings, the number of which is equal to or more than the number n calculated from the following equation n=(Breakdown voltage Vbr (V))/100, and the spacing between the adjacent guard rings is set at 1 μm or less.